Product Preview

F2, HERIC Module with PCM and NTC

The FPF2G75FH07BP is the HERIC topology which is providing a high efficiency solution for the solar application. And the integrated high speed field stop IGBTs are providing lower conduction and switching losses. And the pre–applied PCM requires no additional process of the thermal interface material printing. Furthermore, the screw clamp provides a fast and reliable mounting method.

Electrical Features

- High Efficiency
- Low Conduction and Switching Losses
- High Speed Field Stop IGBT
- Built-in NTC for Temperature Monitoring
- This is a Pb-Free Device

Mechanical Features

- Compact Size: F2 Package
- Soldering Pin
- Al₂O₃ Substrate with Low Thermal Resistance
- Pre-applied PCM (Phase Change Material)

Applications

• Solar Inverter

Related Materials

- AN-5077: Design Considerations for High Power Module (HPM)
- AN–4186: F1 and F2 Modules with Pre–applied Phase Change Material (PCM)

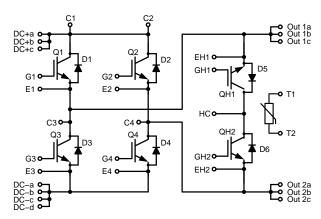


Figure 1. Internal Circuit Diagram



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CODE: F2
CASE MODFS

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

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PACKAGE MARKING AND ORDERING INFORMATION

Device	Device Marking	Package	PCM	Packing Type	Quantity / Tray
FPF2G75FH07BP	FPF2G75FH07BP	F2	0	Tray	14

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C unless otherwise noted)

Symbol	Description	Condition	Rating	Units
IGBT		<u> </u>		
V _{CES}	Collector–Emitter Voltage		650	V
V_{GES}	Gate–Emitter Voltage		±25	V
I _C	Continuous Collector Current	T _C = 80°C, T _{Jmax} = 175°C	75	Α
I _{CM}	Pulsed Collector Current	limited by T _{Jmax}	150	Α
P_{D}	Maximum Power Dissipation		236	W
TJ	Operating Junction Temperature		-40 to +150	°C
FULL-BRIDG	GE DIODE (D1, D2, D3, D4)			•
V_{RRM}	Peak Repetitive Reverse Voltage			V
I _F	Continuous Forward Current	T _C = 80°C, T _{Jmax} = 175°C	50	Α
I _{FM}	Maximum Forward Current			А
P_{D}	Maximum Power Dissipation		208	W
TJ	Operating Junction Temperature	-40 to +150	°C	
HERIC DIOD	E (D5, D6)			•
V_{RRM}	Peak Repetitive Reverse Voltage		650	V
l _F	Continuous Forward Current	T _C = 80°C, T _{Jmax} = 175°C	75	Α
I _{FM}	Maximum Forward Current		150	Α
P_{D}	Maximum Power Dissipation		272	W
TJ	Operating Junction Temperature		-40 to +150	°C
MODULE				
T _{STG}	Storage Temperature (Note 1)		-40 to +125	°C
V_{ISO}	Isolation Voltage	AC 1 min.	2500	V
lsoMaterial	Internal Isolation Material		Al ₂ O ₃	_
T _{MOUNT}	Mounting Torque (Note 2)	M4	2.4	N∙m
Creepage	Terminal to Heat Sink	·	11.5	mm
	Terminal to Terminal	6.3	mm	
Clearance	Terminal to Heat Sink		10.0	mm
	Terminal to Terminal		5.0	mm

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. In the case of PCM pre–applied module, please refer to the application note (AN–4186)

2. Recommendable value : 2.0 ~ 2.4 Nm (M4)

ELECTRICAL CHARACTERISTICS $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Conditions	Min	Тур	Max	Units
IGBT OFF CHARA	ACTERISTICS					
BV _{CES}	Collector–Emitter Breakdown Voltage	V _{GE} = 0 V, I _C = 1 mA	650	_	-	V
I _{CES}	Collector Cut-off Current	V _{CE} = V _{CES} , V _{GE} = 0 V	_	_	250	μΑ
I _{GES}	Gate-Emitter Leakage Current	V _{GE} = V _{GES} , V _{CE} = 0 V	-	_	±2	μΑ
ON CHARA	CTERISTICS					•
V _{GE(th)}	Gate-Emitter Threshold Voltage	$V_{GE} = V_{CE}$, $I_C = 75$ mA	4.2	5.4	6.8	V
V _{CE(sat)}	Collector–Emitter Saturation Voltage	I _C = 75 A, V _{GE} = 15 V	_	1.58	2.2	V
		I _C = 75 A, V _{GE} = 15 V, T _C = 125°C	-	1.85	-	V
R _{LEAD}	Lead Resistance of Pin to Chip	per Chip	-	3.3	-	mΩ
SWITCHING	CHARACTERISTICS (Q3-D5 / Q4-D6)			•	•	
t _{d(on)}	Turn-On Delay Time	V _{CC} = 300 V	_	75	_	ns
t _r	Rise Time	I _C = 75 A V _{GE} = 15 V	_	54	_	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 30 \Omega$ Inductive Load $T_C = 25^{\circ}C$	_	380	_	ns
t _f	Fall Time		_	52	_	ns
E _{ON}	Turn-On Switching Loss per Pulse		_	0.93	_	mJ
E _{OFF}	Turn-Off Switching Loss per Pulse	1	_	1.26	_	mJ
t _{d(on)}	Turn-On Delay Time	V _{CC} = 300 V	_	65	_	ns
t _r	Rise Time	I _C = 75 A	_	59	_	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GE} = 15 \text{ V}$ $R_{G} = 30 \Omega$ Inductive Load $T_{C} = 125^{\circ}\text{C}$	_	410	_	ns
t _f	Fall Time		_	52	_	ns
E _{ON}	Turn-On Switching Loss per Pulse			1.66	_	mJ
E _{OFF}	Turn-Off Switching Loss per Pulse			1.53	_	mJ
Qg	Total Gate Charge	V _{CC} = 300 V, I _C = 75 A,		123	-	nC
L g	Total Gute Gharge	V _{GE} = 0 ~ 15 V		120		
$R_{\theta JC}$	Thermal Resistance of Junction to Case	per Chip	-	_	0.63	°C/W
$R_{\theta CH}$	Thermal Resistance of Case to Heat sink	per Chip, λ _{PCM} = 3.4 W/mK	_	0.49	-	°C/W
FULL-BRID	GE DIODE (D1, D2, D3, D4)					
V _F	Diode Forward Voltage	I _F = 50 A	-	2.03	2.8	V
		I _F = 50 A, T _C = 125°C	_	1.7	-	V
R _{LEAD}	Lead Resistance of Pin to Chip	per Chip	-	3.4	-	mΩ
I_R	Reverse Leakage Current	V _R = 650 V	_	_	250	μΑ
I _{rr}	Reverse Recovery Current	V _R = 300 V, I _F = 50 A di / dt = 1300 A/μs	_	28	_	Α
Q_{rr}	Reverse Recovery Charge	$T_{C} = 25^{\circ}C$	_	0.5	_	μС
E _{rec}	Reverse Recovery Energy		_	51	_	μJ
I _{rr}	Reverse Recovery Current	$V_R = 300 \text{ V}, I_F = 50 \text{ A}$ di / dt = 1300 A/µs	_	40	-	Α
Q_{rr}	Reverse Recovery Charge	$T_{C} = 125^{\circ}C$	_	1.2	-	μС
E _{rec}	Reverse Recovery Energy	-	_	145	-	μJ
$R_{\theta JC}$	Thermal Resistance of Junction to Case	per Chip	-	_	0.72	°C/W
$R_{\theta CH}$	Thermal Resistance of Case to Heat sink	per Chip, λ _{PCM} = 3.4 W/mK	-	0.38	_	°C/W
HERIC DIOE	DE (D5, D6)					
V _F	Diode Forward Voltage	I _F = 75 A	-	2.28	2.9	V
	I _F = 75 A, T _C = 125°C	-	1.74	_	V	
R _{LEAD}	Lead Resistance of Pin to Chip	per Chip	-	1.1	_	mΩ
I _R	Reverse Leakage Current	V _R = 650 V	_	_	250	μΑ

ELECTRICAL CHARACTERISTICS $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Conditions	Min	Тур	Max	Units
HERIC DIO	DE (D5, D6)				•	
I _{rr}	Reverse Recovery Current	$V_R = 300 \text{ V}, I_F = 75 \text{ A}$ di / dt = 1220 A/ μ s $T_C = 25^{\circ}\text{C}$	_	32	_	Α
Q_{rr}	Reverse Recovery Charge		-	0.79	-	μС
E _{rec}	Reverse Recovery Energy		-	113	-	μJ
I _{rr}	Reverse Recovery Current	$V_R = 300 \text{ V}, I_F = 75 \text{ A}$ di / dt = 1220 A/ μ s $T_C = 125^{\circ}\text{C}$	-	52	-	Α
Q_{rr}	Reverse Recovery Charge		_	1.9	-	μС
E _{rec}	Reverse Recovery Energy		-	288	-	μJ
$R_{\theta JC}$	Thermal Resistance of Junction to Case	per Chip	-	_	0.55	°C/W
$R_{\theta CH}$	Thermal Resistance of Case to Heat sink	per Chip, λ _{PCM} = 3.4 W/mK	-	0.39	-	°C/W
NTC (Therm	nistor)	•	-	-	-	•
R _{NTC}	Rated Resistance	T _C = 25°C	_	10	_	kΩ
		T _C = 100°C	-	936	-	Ω
	Tolerance	T _C = 25°C	-3	_	+3	%
P_{D}	Power Dissipation	T _C = 25°C	_	-	20	mW
B _{Value}	B-Constant	B _{25/50}	_	3450	-	K
		B _{25/100}	_	3513	_	K

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL CHARACTERISTICS - IGBT

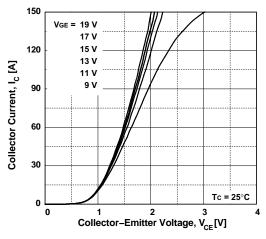


Figure 2. Output Characteristics

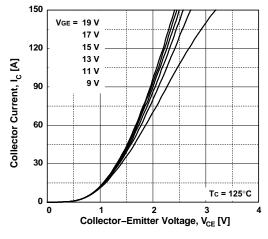


Figure 3. Output Characteristics

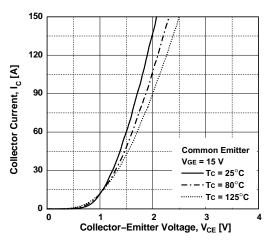


Figure 4. Saturation Voltage Characteristics

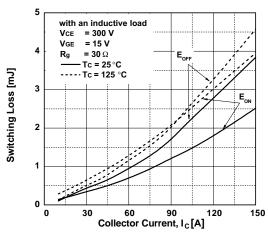


Figure 5. Switching Loss vs. Collector Current

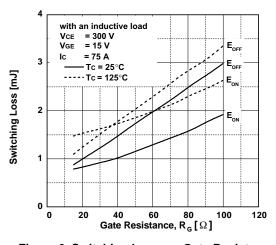


Figure 6. Switching Loss vs. Gate Resistance

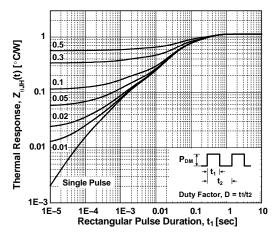


Figure 7. Transient Thermal Impedance

TYPICAL CHARACTERISTICS - FULL-BRIDGE DIODE

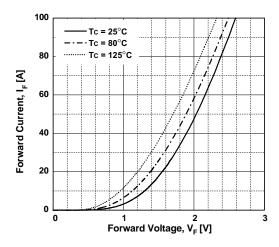


Figure 8. Forward Voltage Drop

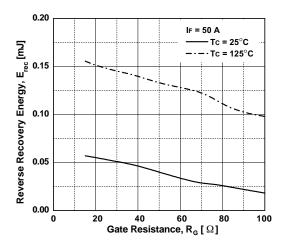


Figure 10. Reverse Recovery Energy vs. Gate Resistance

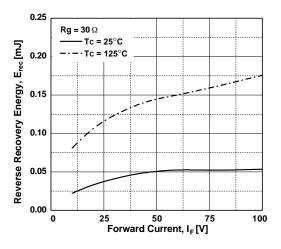


Figure 9. Reverse Recovery Energy vs.
Forward Current

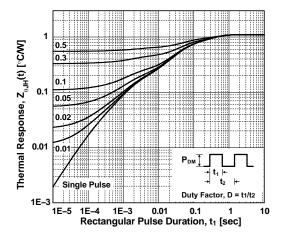


Figure 11. Transient Thermal Impedance

TYPICAL CHARACTERISTICS - HERIC DIODE

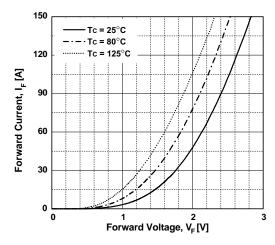


Figure 12. Forward Voltage Drop

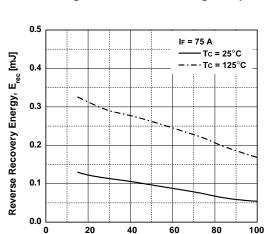


Figure 14. Reverse Recovery Energy vs. Gate Resistance

Gate Resistance, $R_G[\Omega]$

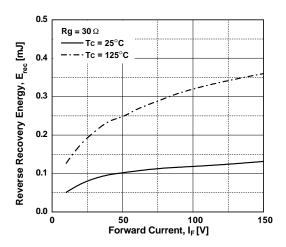


Figure 13. Reverse Recovery Energy vs. Forward Current

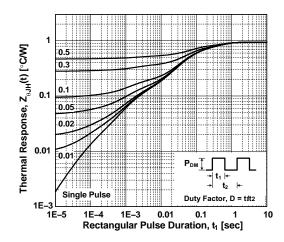
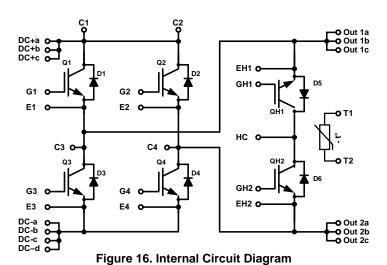
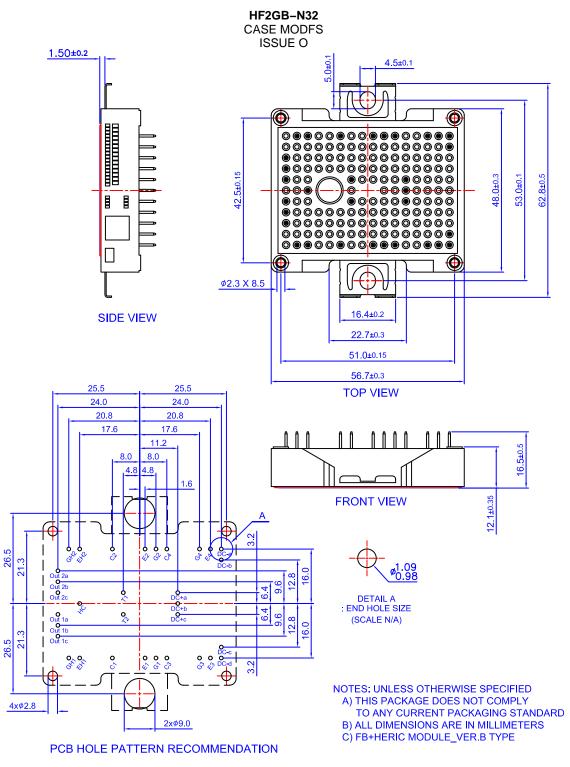


Figure 15. Transient Thermal Impedance



PACKAGE DIMENSIONS



- PIN-GRID 3.2mm
- TOLERANCE OF PCB HOLE PATTERN Φ 0.1

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